

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.095C1	APPLICATION NO. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Agarwal, et al.	
		FILING DATE Herewith	GROUP Unknown

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	4,761,386	8/2/88	Buynoski			
	4,823,182	4/18/89	Okumura			
	4,884,123	11/28/89	Dixit, et al.			
	4,895,770	1/23/90	Schintlmeister, et al.			
	4,920,071	4/24/90	Thomas			
	5,225,771	7/6/93	Leedy			
	5,248,903	9/28/93	Heim			
	5,298,333	3/29/94	Maixner, et al.			
	5,364,803	11/15/94	Lur, et al.			
	5,391,516	2/21/95	Wojnarowski, et al.			
	5,441,904	8/15/95	Kim, et al.			
	5,486,492	1/23/96	Yamamoto, et al.			
	5,506,499	4/9/96	Puar			
	5,541,427	7/30/96	Chappell, et al.			
	5,593,903	1/14/97	Beckenbaugh, et al.			
	5,668,394	9/16/97	Lur, et al.			
	5,684,304	11/4/97	Smears			
	5,693,377	12/2/97	Westmoreland, et al.			
	5,720,098	2/24/98	Kister			
	5,742,174	4/21/98	Kister, et al.			
	5,837,598	11/17/98	Aronowitz, et al.			
	5,851,680	12/22/98	Heau			
	5,920,081	7/6/99	Chen, et al.			
	5,962,867	10/5/99	Liu			
	5,968,594	10/19/99	Hu, et al.			
	5,994,716	11/30/99	Ikeya, et al.			
	6,028,360	2/22/00	Nakamura, et al.			
V	6,017,818	1/25/00	Lu			

EXAMINER	<i>Shannon J. Lee</i>	DATE CONSIDERED	3/18/05
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.095C1	APPLICATION NO. Unknown <i>10687086</i>
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Agarwal, et al.	
(USE SEVERAL SHEETS IF NECESSARY)		FILING DATE Herewith	GROUP Unknown

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
<i>SRL</i>	6,069,482	5/30/00	Hilton				
<i>SRL</i>	6,133,582	10/17/00	Osann, Jr., et al.				
<i>SRL</i>	6,200,649	3/13/01	Dearnaley				
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>SRL</i>	EP 0854 505 A2	7/22/98	Europe				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
<i>SRL</i>	Baker, et al. "Combined X-Ray Photoelectron/Auger Electron Spectroscopy/Glancing Angle X-Ray diffraction/Extended X-Ray Absorption Fine Structure Investigation of TiBxNy Coatings". J. Vac. Sci. Technol., A 15(2), pp. 284-291, March/April 1997
<i>SRL</i>	Sade, et al., "Characterization of TiB ₂ /TiSi ₂ Bilayer Structure Deposited By Sputtering", Mat. Res. Soc. Symp. Proc., Vol. 402, pp. 131-136, 1996

H:\DOCS\KJL\KJL-2360.DOC
100203

EXAMINER <i>Shouravey H.</i>	DATE CONSIDERED <i>3/18/05</i>
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	